TOSHIBA Field Effect Transistor Silicon N Channel MOS Type ($L^2-\pi$ -MOSV)

2SK2311

Chopper Regulator, DC–DC Converter and Switching Regulator Applications

- 4-V gate drive
- Low drain-source ON resistance $: R_{DS} (ON) = 36 \text{ m}\Omega (typ.)$
- High forward transfer admittance $|Y_{fs}| = 16 \text{ S (typ.)}$
- Low leakage current $: I_{DSS} = 100 \ \mu A \ (max) \ (V_{DS} = 60 \ V)$
- Enhancement mode $: V_{th} = 0.8 \sim 2.0 \text{ V} (V_{DS} = 10 \text{ V}, \text{ ID} = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit	
Drain-source voltage		V _{DSS}	60	V	
Drain-gate voltage (R	_{GS} = 20 kΩ)	V _{DGR}	60	V	
Gate-source voltage		V _{GSS}	±20	V	
Drain current	DC (Note 1)	Ι _D	25	А	
	Pulse (Note 1)	I _{DP}	100	А	
Drain power dissipatio	n (Tc = 25°C)	PD	40	W	
Single pulse avalanche	e energy (Note 2)	E _{AS}	156	mJ	
Avalanche current		I _{AR}	25	А	
Repetitive avalanche e	energy (Note 3)	E _{AR}	3.5	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature r	ange	T _{stg}	-55~150	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

Thermal Characteristics

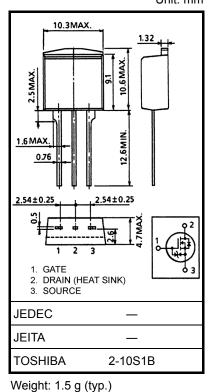
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch−c)}	3.125	°C / W
Thermal resistance, channel to ambient	R _{th (ch−a)}	83.3	°C / W

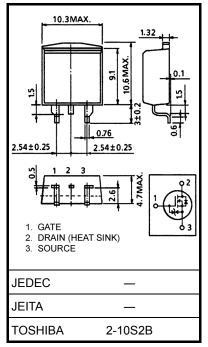


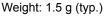
Note 2: V_{DD} = 25 V, T_{ch} = 25°C (initial), L = 339 µH, R_G = 25 Ω , I_{AR} = 25 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.







Unit: mm

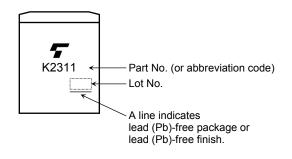
Electrical Characteristics (Ta = 25°C)

Chara	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	urrent	I _{GSS}	V_{GS} = ±16 V, V_{DS} = 0 V	_		±10	μA
Drain cut-off cu	rrent	IDSS	V _{DS} = 60 V, V _{GS} = 0 V		_	100	μA
Drain-source bi	reakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	60	_	_	V
Gate threshold	voltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	0.8		2.0	V
Drain-source ON resistance		R _{DS (ON)}	V _{GS} = 4 V, I _D = 12 A	-	57	80	mΩ
			V _{GS} = 10 V, I _D = 12 A		36	46	11152
Forward transfe	r admittance	Y _{fs}	V _{DS} = 10 V, I _D = 12 A	10	16	_	S
Input capacitant	ce	C _{iss}			1000		
Reverse transfer capacitance		C _{rss}	C _{rss} V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz		200	_	pF
Output capacitance		C _{oss}			550	_	
Switching time	Rise time	tr	$V_{GS} \stackrel{10 \text{ V}}{_{0 \text{ V}}} \int I_{D} = 12 \text{ A} \\ V_{GS} \stackrel{10 \text{ V}}{_{0 \text{ V}}} \int I_{D} = 12 \text{ A} \\ V_{OUT} \stackrel{V}{_{0 \text{ V}}} \\ R_{L} = 2.5 \Omega \\ V_{DD} = 30 \text{ V}$	_	20	_	ns
	Turn-on time	t _{on}		_	30	_	
	Fall time	t _f			55	_	
	Turn-off time	toff	$Duty \leq 1\%, t_{\rm W} = 10 \ \mu s$		130		
Total gate charge (Gate-source plus gate-drain)		Qg		_	38	_	
Gate-source charge		Q _{gs}	V _{DD} ≈ 48 V, V _{GS} = 10 V, I _D = 25 A		25	_	nC
Gate-drain ("miller") charge		Q _{gd}			13	_	

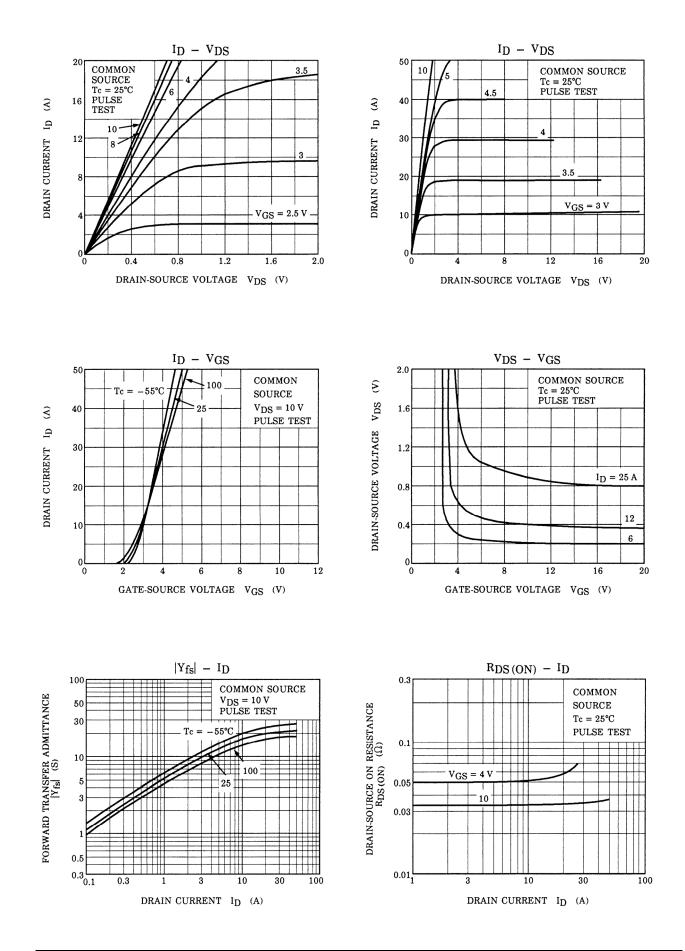
Source–Drain Ratings and Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	—	_	_	25	А
Pulse drain reverse current (Note 1)	I _{DRP}	—	_	_	100	А
Forward voltage (diode)	V _{DSF}	I _{DR} = 25 A, V _{GS} = 0 V	_	_	-1.8	V
Reverse recovery time	t _{rr}	I _{DR} = 25 A, V _{GS} = 0 V		50		ns
Reverse recovery charge	Q _{rr}	dI _{DR} / dt = 50 A / μs	_	35	_	μC

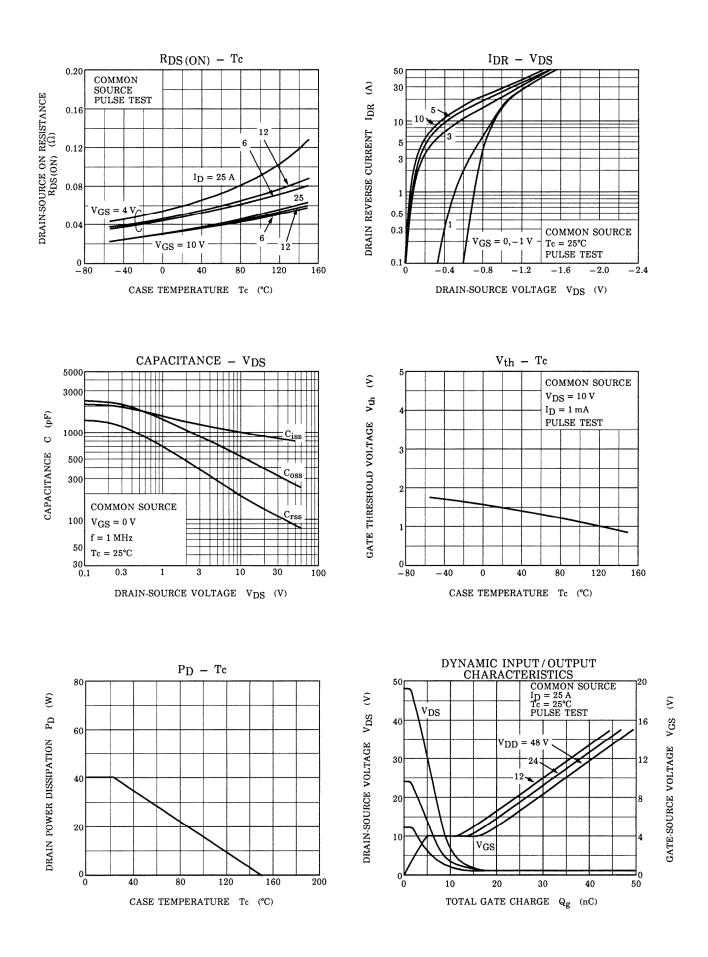
Marking

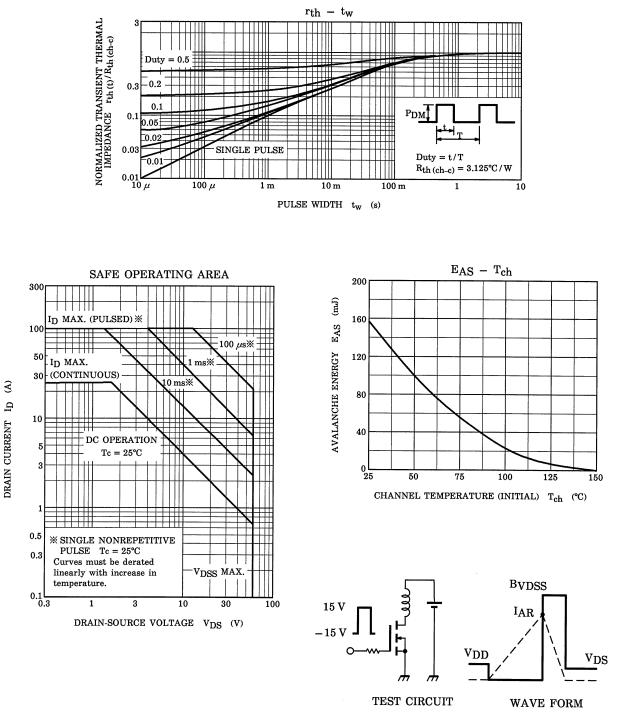


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 $R_{G} = 25 \Omega$ $V_{DD} = 25 V, L = 339 \mu H$ $EAS = \frac{1}{2} \cdot L \cdot I^{2} \cdot \left(\frac{BVDSS}{BVDSS - VDD}\right)$

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